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(54) **ENHANCED IMPEDANCE MEASUREMENT USING CTMU**

(71) Applicant: **Microchip Technology Incorporated**, Chandler, AZ (US)

(72) Inventors: **Bogdan Bolocan**, Eggenstein-Leopoldshafen (DE); **Ezana Halle**, Chandler, AZ (US); **Pat Richards**, Peoria, AZ (US)

(73) Assignee: **Microchip Technology Incorporated**, Chandler, AZ (US)

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Primary Examiner — Raul J Rios Russo

(74) *Attorney, Agent, or Firm* — SLAYDEN GRUBERT BEARD PLLC

(57) **ABSTRACT**

A method and apparatus for measuring an unknown impedance. The apparatus comprises a first input to receive a first signal generated by a first portion of a sensor circuit, the first portion comprising an unknown impedance and a first known resistance, the unknown impedance to vary based upon a phenomenon to be measured by the sensor circuit. The apparatus also comprises a second input to receive a second signal generated by a second portion of the sensor circuit, the second portion of the sensor circuit comprising a known impedance and a second known resistance. And the apparatus comprises control logic to, based on a difference in time at which each of the first input and the second input reach a reference voltage, determine a measurement of the sensor circuit.

20 Claims, 9 Drawing Sheets

